

Inspection microscope BXFM for the industry with an excellent price performance ratio



Advanced options for system combinations:

The BXFM is a reflected light microscope for metallurgy and materials applications.

The BXFM microscope concept brings together all the capabilities needed for thorough inspection of a wide variety of electronic devices and semiconductor components. As well as excellent cost-efficiency, it offers a compact design based on advanced ergonomics.

The comprehensive list of features includes top-quality UIS optics backed by a full range of accessories from Olympus as well as from Ryf AG, and an arm-integrated reflected light illuminator for easier component.

The BXFM is a compact and modular microscope for research applications. The microscope can be fully integrated in custom made systems.

Universal stand Olympus STU-2 / RUS-Ryf AG

This stand is designed for observation and photomicrography of specimens which are too large for a stand. A structure based on dual horizontal poles and linear ball bearings ensures smooth horizontal movement and rotation. The mechanism can be tilted forward, backward, right and left, allowing quick and precise approach to the chosen observation area.



Range of tilting observation tubes to assist operator comfort

U-TBI3 and U-ETBI tilting tubes are provided for binocular observation, and the U-SWETTR observation tube for documentation / photomicrography. This range of choice lets each operator achieve the most suitable eyepoint and an ergonomic posture, resulting in greatly reduced fatigue for long-duration observations.



UIS optics for bright, clear observation images

THE BX41M's range of objectives includes units for ultralong working distance and ultra high magnifications as well as universal objectives, which are applicable to all observation methods. Careful selection ensures smooth, precise inspections of any and every sample.

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Frame	The BXFM-S unit incorporates a compact reflected light brightfield illuminator with a depth of only 290 mm from the optical axis to rear of the lamp housing. The BXFM unit accommodates the reflected light brightfield/darkfield and fluorescence illuminators.	
Revolving Nosepiece	Motorized revolving nosepiece is available for installation into the system.	
Objectives	Full line-up of UIS objectives for all observation methods including brightfield, darkfield, Nomarski DIC, polarized light and fluorescence microscopy	
Observation Tubes	Binocular tubes, trinocular tubes: widefield (F.N. 22), superwidefield (F.N. 26.5) inverted or erect image, special ergonomic tube available	
Condensers	Three condensors for reflected light to feature all reflected light contrast methods including fluorescene	
Illumination	100W halogen, 100W halogen fiber illumination, 100W mercury for reflected light	
Stands	Normal, large stand, Ryf Universal stand with boom and Olympus Stand with boom	
Contrast Methods	Reflected brightfield, darkfield, Nomarski DIC, polarisation, fluorescence	
Applications	All applications which require to mount microscope components to special set-ups	
Special Accesories	Infrared components, three different Nomarski DIC prisms (standard, high contrast, high resolution)	

BXFM specifications

		BXFM	BXFM-S	
Optical system		UIS optical system		
Objectives		UIS objectives		
	Eyepieces	UIS eye	epieces	
Observation tubes		UIS observation tubes		
Revolving nosepieces		UIS revolving nosepieces		
Microscope frame		Stroke 30mm, rotation of fine focus knob: 200µm, minimum adjustment gradation: 2µm, with torque adjustment for coarse knob		
Illuminators		BX-RLA2: 100W halogen, etc. BF/DF/DIC/KPO BX-URA2: 100W mercury lamp, etc. fluorescence illuminator	BX-KMAS: 100W halogen fiber illumination BF/DIC/KPO	

BXFM-S dimensions (unit: mm)

